

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10686560	LEE ET AL.
<b>Examiner</b>		<b>Art Unit</b>
Yuen, Kan		2616

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	204	5/10/2007	ky
370	208	5/10/2007	ky
370	328	5/10/2007	ky
370	342	5/10/2007	ky
370	335	5/10/2007	ky
370	321	5/10/2007	ky
370	330	5/10/2007	ky
370	442	5/10/2007	ky
370	465	5/10/2007	ky

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST SEARCH CONSULTED WITH SPE AND PRIMARY EXAMINER	5/10/2007	KY
INVENTORSHIP SEARCH	5/10/2007	KY
MANUAL SEARCH CLASS 370 SUBCLASS 335	5/10/2007	KY
PLUS SEARCH	5/10/2007	KY

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	INTERFERENCE SEARCH PRINTOUT (SEE SEARCH PRINTOUT)	2/25/2008	KY